

EVENT BASED TEST SYSTEM HAVING IMPROVED
SEMICONDUCTOR CHARACTERIZATION MAP

Abstract of the Disclosure

An event based test system having [an improved] 6L
5 characterization tool for semiconductor device testing. The characterization map provides multi-dimensional views of device performance for debug of the design, and identification of performance weaknesses. The characterization map tool exploits the capabilities of the 10 event based test system. The multi-dimensional views include a checkerboard map such as displaying pins versus time, a shmoo plot showing pass-fail boundary points relative to predetermined parameters, or a margin map showing a pass/fail range for pins corresponding with timing 15 changes in one or more events.

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